

VALVE ELECTRONIC **CV 1695**GENERAL POST OFFICE: F-IN-C (S)

(POVT 133)

Specification: G.P.O./CV1695/ Issue 2 Dated: 10th March, 1948. To be read in conjunction with K 1001	<table border="1"> <tr> <th colspan="2"><u>SECURITY</u></th></tr> <tr> <td><u>Specification</u></td><td><u>Valve</u></td></tr> <tr> <td>Restricted</td><td>Restricted</td></tr> </table>	<u>SECURITY</u>		<u>Specification</u>	<u>Valve</u>	Restricted	Restricted
<u>SECURITY</u>							
<u>Specification</u>	<u>Valve</u>						
Restricted	Restricted						

→ indicates a change

<u>TYPE OF VALVE:</u> Double-diode <u>CATHODE:</u> Indirectly heated <u>ENVELOPE:</u> Unmetallised glass <u>PROTOTYPE</u> D D L 13			<u>MARKING</u> See K 1001/4		
<u>RATING</u>			Note	<u>BASE</u> British 5-pin (B5)	
				<u>CONNEXIONS</u>	
				Pin	Electrode
Heater current (A) 0.2				1	Diode 1
Nominal heater voltage (V) 13.0				2	Diode 2
Max. diode voltage (V) 200				3	Heater
Max. mean diode current (mA) 10.0				4	Heater
			5	Cathode	
			<u>DIMENSIONS</u> See K1001/A1/D1		
			Dimension	Min.	Max.
			A (m m)	-	96
			B (m m)	-	30

To be performed in addition to those applicable in K1001

	TEST CONDITIONS					TEST	LIMITS		No. Tested	Note
							Min.	Max.		
(a)	Test Voltage 500 Volts D.C.					INSULATION (μ egohms)				
						(i) Cathode to heater	-	-	1%	1, 2
						(ii) Diodes to cathode	100	-	1%	1
						(iii) Between any other two electrodes	500	-	1%	1
						(iv) Between any electrode and the metallic shell of the base.	500	-	1%	1
	I h (A)	Id 1 (μ A)	Id 2 (μ A)	Vd 1 (V)	Vd 2 (V)					
(b)	0.2	-	-	-	-	Ageing (hours)	200	-	100%	3
(c)	0.2	-	-	-	-	Vh (V)	11.7	14.3	100%	1
(d)	0.2	1.0	-	Read	-	Vd 1 (V)	-0.3	-1.2	100%	1
(e)	0.2	-	1.0	-	Read	Vd 2 (V)	-0.3	-1.2	100%	1
(f)	0.2	Read	-	0	-	Id 1 change (mA)	3.5	-	100%	1
				2						
(g)	0.2.	-	Read	0	-	Id 2 change (mA)	3.5	-	100%	1
				2						

NOTES

1. Before commencing the test the valve shall be pre-heated for 15 minutes with 0.2 amps flowing through the heater.
2. To be performed in accordance with K1001/5.3
3. Ageing condition shall be applied with Diode 1 and Diode 2 strapped to Cathode, and shall be applied before all other tests.